

FORM PTO-1449		U.S. Department of Commerce Patent and Trademark Office		Atty. Docket No. FIS920030239US1	Application No. 10/707,690
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)		Applicant Huilong ZHU et al.			
		Filing Date 01/05/2004	Group 1765 2818		

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DV		US 2002/0063292 A1	5-30-2002	Armstrong et al.			
		US 2003/0032261 A1	2-13-2003	Yeh et al.			
		US 2003/0040158 A1	2-27-2003	Saitoh			
		US 2004/0238914 A1	12-2-2004	Deshpande et al.			
		US 2004/0262784 A1	12-30-2004	Doris et al.			
		US 2005/0040460 A1	2-24-2005	Chidambaram et al.			
		US 2005/0082634 A1	4-21-2005	Doris et al.			
		US 2005/0093030 A1	5-5-2005	Doris et al.			
		US 2005/0098829 A1	5-12-2005	Doris et al.			
		US 2005/0106799 A1	5-19-2005	Doris et al.			
		US 2005/0145954 A1	7-7-2005	Zhu et al.			
		US 2005/0148146 A1	7-7-2005	Doris et al.			
		US 2005/0194699 A1	9-8-2005	Belyansky et al.			
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		US 2005/0280051 A1	12-22-2005	Chidambaram et al.			
		US 2005/0282325 A1	12-22-2005	Belyansky et al.			
		US 2006/0027868 A1	2-9-2006	Doris et al.			
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		6,483,171	11-19-2002	Forbes et al.			
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		6,825,529	11-30-2004	Chidambaram et al.			
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		6,974,981	12-13-2005	Chidambaram et al.			
DV		6,977,194	12-20-2005	Belyansky et al.			

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
DV		JP 64-76755	3-22-1989	Japan				X

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	<i>forland</i>	DATE CONSIDERED	09/15/06
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

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U.S. PATENT DOCUMENTS							
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
DV		G. Zhang, et al., "A New 'Mixed-Mode' Reliability Degradation Mechanism in Advanced Si and SiGe Bipolar Transistors." IEEE Transactions on Electron Devices, vol. 49, no. 12, December 2002, pp. 2151-56.					
		H.S. Momose, et al., "Temperature Dependence of Emitter-Base Reverse Stress Degradation and its Mechanism Analyzed by MOS Structures." 1989 IEEE, Paper 6.2, pp. 140-143.					
		C.J. Huang, et al., "Temperature Dependence and Post-Stress Recovery of Hot Electron Degradation Effects in Bipolar Transistors." IEEE 1991, Bipolar Circuits and Technology Meeting 7.5, pp. 170-173.					
		S.R. Sheng, et al., "Degradation and Recovery of SiGe HBTs Following Radiation and Hot-Carrier Stressing." pp. 14-15.					
		Z. Yang, et al., "Avalanche Current Induced Hot Carrier Degradation in 200 GHz SiGe Heterojunction Bipolar Transistors." pp. 1-5.					
		H. Li, et al., "Design of W-Band VCOs with High Output Power for Potential Application in 77 GHz Automotive Radar Systems." 2003, IEEE GaAs Digest, pp. 263-66.					
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		J.H. Van Der Merwe, "Regular Articles". Journal of Applied Physics, Volume 34, No. 1, January 1963, pp. 117-122.					
		J.W. Matthews, et al., "Defects in Epitaxial Multilayers". Journal of Crystal Growth 27 (1974), pp. 118-125.					
		Subramanian S. Iyer, et al. "Heterojunction Bipolar Transistors Using Si-Ge Alloys". IEEE Transactions on Electron Devices, Vol. 36, No. 10, October 1989, pp. 2043-2064					
		R.H.M. Van De Leur, et al., "Critical Thickness for Pseudomorphic Growth of Si/Ge Alloys and Superlattices". J. Appl. Phys. 64 (6), 15 September 1988, pp. 3043-3050					
		D.C. Houghton, et al., "Equilibrium Critical Thickness for SI 1-x GEx Strained Layers on (100) Si". Appl. Phys. Lett. 56 (5), 29 January 1990, pp. 460-462					
DV		Q. Quyang et al., "Two-Dimensional Bandgap Engineering in a Novel Si/SiGe pMOSFET with Enhanced Device Performance and Scalability". 2000, IEEE, pp. 151-154.					
EXAMINER <i>Shulard</i>				DATE CONSIDERED 09/15/06			
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INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) FIS920030239US1	Application Number 10/707,690		
				Applicant(s) Stephen W. Bedell, et al.			
				Filing Date 01/05/04	Group Art Unit -1765-- 2818		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
PV		5,940,716	08/17/99	Jin, et al.			
		5,981,356	11/09/99	Hsueh, et al.			
		6,080,637	06/27/00	Huang, et al.			
		6,093,621	07/25/00	Tseng			
↓ PV		6,583,060	06/24/03	Trivedi			
U.S. PATENT APPLICATION PUBLICATIONS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
FOREIGN PATENT DOCUMENTS							
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation
							YES
							NO
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
EXAMINER				DATE CONSIDERED		<i>09/15/06</i>	
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FORM PTO-1449 (Modified)	ATTY. DOCKET NO. FIS9-2003-0239US1	SERIAL NO. 10/707,690
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	APPLICANT: Steven W. Bedell, et al.	
(Use several sheets if necessary)	FILING DATE: 1-5-2004	GROUP: Unassigned 2818

REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS					
EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
DV		6,228,694 B1	5/8/2001	Doyle et al.			
		6,406,973 B1	6/18/2002	Lee			
		6,281,532 B1	8/28/2001	Doyle et al.			
		5,683,934	11/4/97	Candelaria			
		6,368,931 B1	4/9/2002	Kuhn, et al.			
		5,310,446	5/10/94	Konishi et al.			
		4,853,076	8/1/89	Tsaur et al.			
		US 2002/0090791 A1	7/11/2002	Doyle et al.			
		US 2002/0074598 A1	6/20/2002	Doyle et al.			
		6,509,618 B2	7/21/2003	Jan et al.			
		6,476,462 B2	11/5/2002	Shimizu et al.			
		6,362,082 B1	3/26/2002	Doyle et al.			
		6,228,694 B1	5/8/2001	Doyle et al.			
		5,565,697	10/15/96	Asakawa et al.			
		US 2003/0040158 A1	2/27/2003	Saitoh			
		US 2002/0086472 A1	7/4/2002	Roberds et al.			
		6,521,964 B1	2/18/2003	Jan et al.			
DV		6,506,652	01/14/03	Jan, et al.			

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)		

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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		APPLICANT: Steven W. Bedell, et al.					
(Use several sheets if necessary)		JAN 09 2004 PATENT & TRADEMARK OFFICE JC66		FILING DATE: 1-5-2004	GROUP: Unassigned 2818		
REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS					
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS		
DV	5,081,513	1/14/1992	Jackson, et al.				
	3,602,841	8/31/1971	McGroddy				
	6,531,740	3/11/2003	Bosco, et al.				
	6,531,369	3/11/2003	Ozkan, et al.				
	6,501,121	12/31/2002	Yu, et al.				
	6,498,358	12/24/2002	Lach, et al.				
	6,493,497	12/10/2002	Randani, et al.				
	6,403,975	6/11/2002	Brunner, et al.				
	6,361,885	3/26/2002	Chou				
	6,255,169	7/3/2001	Li, et al.				
	6,246,095	6/12/2001	Brady, et al.				
	6,165,383	12/26/2000	Chou				
	6,133,071	10/17/2000	Nagai				
	6,046,464	4/4/2000	Schetzina				
DV	6,025,280	2/15/2000	Brady, et al.				
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
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PATENT & TRADEMARK OFFICE U.S. PATENT DOCUMENTS							
EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
DV		5,940,736	8/17/1999	Brady, et al.			
		5,880,040	3/9/1999	Sun, et al.			
		5,861,651	1/19/1999	Brasen, et al.			
		5,679,965	10/21/1997	Schetzina			
		5,670,798	9/23/1997	Schetzina			
		5,561,302	10/1/1996	Candelaria			
		5,471,948	12/5/1995	Burroughes, et al.			
		5,459,346	10/17/1995	Asakawa, et al.			
		5,391,510	2/21/1995	Hsu, et al.			
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		5,108,843	4/28/1992	Ohtaka, et al.			
		5,060,030	10/22/1991	Hoke			
		4,958,213	9/18/1990	Eklund, et al.			
DV		4,665,415	5/12/1987	Esaki, et al.			
FOREIGN PATENT DOCUMENTS							
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REFERENCE DESIGNATION U.S. PATENT DOCUMENTS							
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)	
DV	5,989,978	11/23/1999	Peidous				
	6,284,626	9/4/2001	Kim				
	6,274,444	8/14/2001	Wang				
	6,261,964	7/17/2001	Wu, et al.				
	6,221,735	4/24/2001	Manley, et al.				
	6,117,722	9/12/2000	Wuu, et al.				
	6,107,143	8/22/2000	Park, et al.				
	6,090,684	7/18/2000	Ishitsuka, et al.				
	6,066,545	5/23/2000	Doshi, et al.				
	6,008,126	12/28/1999	Leedy				
	5,946,559	8/31/1999	Leedy				
	5,840,593	11/24/1998	Leedy				
	5,592,018	1/7/1997	Leedy				
	5,592,007	1/7/1997	Leedy				
DV	5,571,741	11/5/1996	Leedy				

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		JAN 09 2004 PATENT & TRADEMARK OFFICE 900 JC		FILING DATE: 1-5-2004	GROUP: Unassigned 2818		
REFERENCE DESIGNATION U.S. PATENT DOCUMENTS							
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS		
PV	5,557,122	9/17/1996	Shrivastava, et al.				
	5,354,695	10/11/1994	Leedy				
	5,134,085	7/28/1992	Gilgen, et al.				
	5,006,913	4/9/1991	Sugahara, et al.				
	4,952,524	8/28/1990	Lee, et al.				
	4,855,245	8/8/1989	Neppl, et al.				
	2002/0086497	07-04-2002	Kwok				
	5,960,297	09-28-1999	Saki				
	6,403,486	06-11-2002	Lou				
	6,284,623	09-04-2001	Zhang et al.				
	2003/0032261	02-13-2003	Yeh et al.				
	2003/0057184	03-27-2003	Yu et al.				
	6,265,317	07-24-2001	Chiu et al.				
	2003/0067035	04-10-2003	Tews et al.				
	6,461,936	10-08-2002	von Ehrenwall				
	6,319,794	11-20-2001	Akatsu et al.				
DV	2001/0009784	07-26-2001	Ma et al.				
FOREIGN PATENT DOCUMENTS							
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EXAMINER <i>Stewart</i>				DATE CONSIDERED 09/15/06			
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OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)						
DV	Kern Rim, et al., "Transconductance Enhancement in Deep Submicron Strained-Si n-MOSFETs", International Electron Devices Meeting, 26, 8, 1, IEEE, September 1998.					
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	F. Ootsuka, et al., "A Highly Dense, High-Performance 130nm node CMOS Technology for Large Scale System-on-a-Chip Application", International Electron Devices Meeting, 23.5.1, IEEE, April 2000.					
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	A. Shimizu, et al., "Local Mechanical-Stress Control (LMC): A New Technique for CMOS-Performance Enhancement", International Electron Devices Meeting, IEEE, March 2001.					
DV	K. Ota, et al., "Novel Locally Strained Channel Technique for high Performance 55nm CMOS", International Electron Devices Meeting, 2.2.1, IEEE, February 2002.					
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